Se	arch	Note	es	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/712,564	MERCADO, ABEL
Examiner	Art Unit
Tuan N. Nguyen	3751

	SEAR	CHED	
Class	Subclass	Date	Examiner
4	255.01 255.05 255.11	6/27/2005	\$/
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TERFERENCE SEARCHED		
Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST BRS TEXT SEARCH ATTACHED	6/27/2005	STY
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